

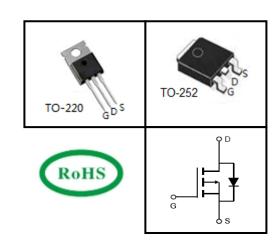
100V P-Channel Trench MOSFET

FEATURES

- Trench Power MOSFET Technology
- Low R_{DS(ON)}
- Low Gate Charge
- Optimized For Fast-switching Applications

APPLICATIONS

- Load Switches
- Battery Switch



Device Marking and Package Information			
Device Package		Marking	
TTP30P10AT	TO-220	30P10AT	
TTD30P10AT	TO-252	30P10AT	

Absolute Maximum Ratings $T_C = 25^{\circ}C$, unless otherwise noted				
Parameter	S. mo	Symbol	Value	Unit
raiametei		Symbol	TO-220, TO-252	
Drain-Source Voltage (V _{GS} = 0V)		V_{DSS}	-100	V
Continuous Drain Current		I _D	-30	А
Pulsed Drain Current	(note1)	I _{DM}	-150	А
Gate-Source Voltage		V_{GSS}	±20	V
Single Pulse Avalanche Energy	(note2)	E _{AS}	54	mJ
Avalanche Current	(note1)	I _{As}	-19	А
Power Dissipation (T _C = 25°C)		P_D	136	W
Operating Junction and Storage Temperature Range		T_J,T_stg	-55~+175	°C

Thermal Resistance				
Parameter	Symbol	Value	Unit	
Farameter	Symbol	TO-220, TO-252	Unit	
Thermal Resistance, Junction-to-Case	R _{thJC}	1.1	12001	
Thermal Resistance, Junction-to-Ambient	R _{thJA}	60	K/W	

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-		rwise noted	Value			
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = -250\mu A$	-100			V
Zeus Cota Valta de Dusia Cumant		$V_{DS} = -100V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			-1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -100V, V _{GS} = 0V, T _J = 150°C			-100	μA
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20V$			±100	nA
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-1.0	-1.7	-3.0	V
D : 0	5	V _{GS} = -10V, I _D = -15A		35	46	mΩ
Drain-Source On-Resistance (Note3)	$R_{DS(on)}$	$V_{GS} = -4.5V, I_{D} = -15A$		38	50	mΩ
Forward Transconductance (Note3)	g _{fs}	V _{DS} = -50V, I _D = -10A		13.6		S
Dynamic						
Input Capacitance	C _{iss}	V 0V		8704		
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = -50V,$		212		pF
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		135		
Total Gate Charge	Q_g			140		
Gate-Source Charge	Q_{gs}	$V_{DD} = -50V, I_{D} = -15A, V_{GS} = -10V$		23		nC
Gate-Drain Charge	Q_{gd}	93		27		
Turn-on Delay Time	t _{d(on)}			20		
Turn-on Rise Time	t _r	$V_{DD} = -50V, I_{D} = -15A,$		80		
Turn-off Delay Time	t _{d(off)}	$R_G = 2.5\Omega$		50		ns
Turn-off Fall Time	t _f			70		
Drain-Source Body Diode Characteris	stics					
Continuous Body Diode Current	I _s	T _C = 25°C			-30	۸
Pulsed Diode Forward Current	I _{SM}				-150	А
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = -15\text{A}, V_{GS} = 0\text{V}$			-1.2	V
Reverse Recovery Time	t _{rr}	I _F = -15A,		90		ns
Reverse Recovery Charge	Q _{rr}	di _F /dt = 100A/μs		70		nC

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = -19A, V_{DD} = 50V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 3. Pulse Test: Pulse width ≤ 300µs, Duty Cycle ≤ 1%

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Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

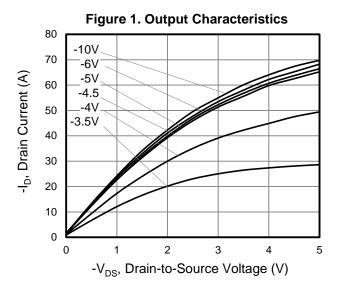


Figure 3. On-Resistance vs. Drain Current

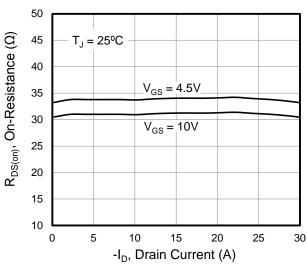


Figure 5. Gate Charge

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Figure 2. Transfer Characteristics $V_{DS} = -5V$ $V_{DS} = -5V$ $T_{J} = 125^{\circ}C$ $T_{J} = 25^{\circ}C$

Figure 4. Capacitance

-V_{GS}, Gate-to-Source Voltage (V)

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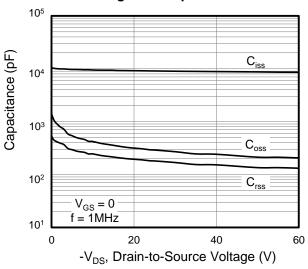
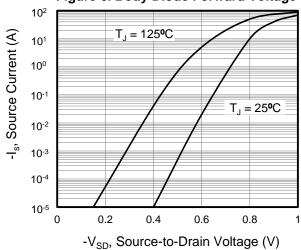


Figure 6. Body Diode Forward Voltage





Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted

Figure 7. On-Resistance vs.

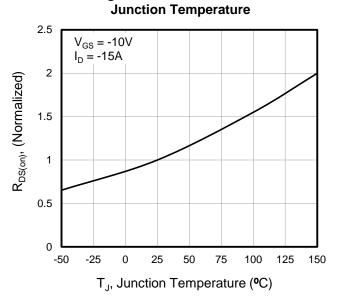


Figure 8. Threshold Voltage vs. Junction Temperature

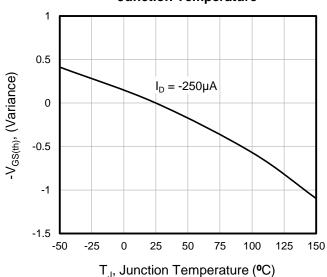
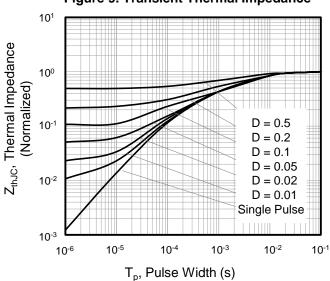


Figure 9. Transient Thermal Impedance



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Figure A: Gate Charge Test Circuit and Waveform

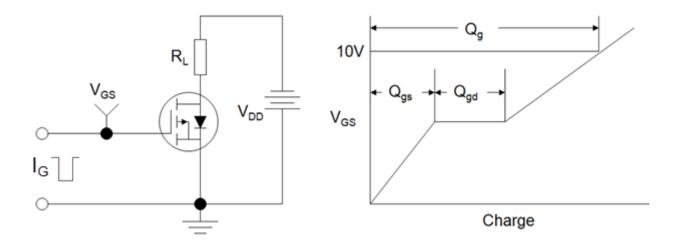


Figure B: Resistive Switching Test Circuit and Waveform

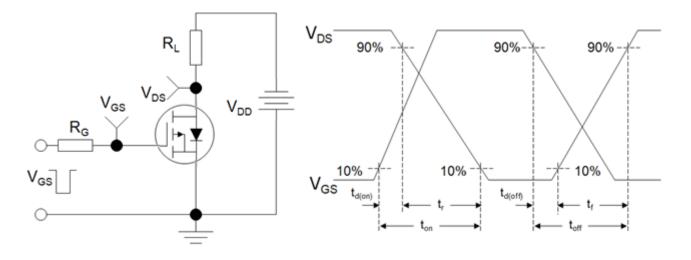
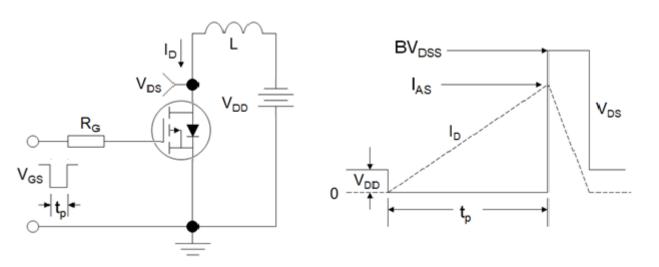
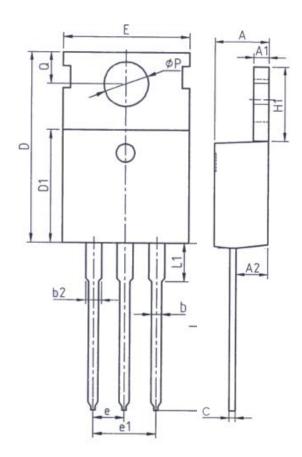


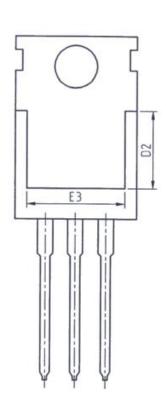
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



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TO-220

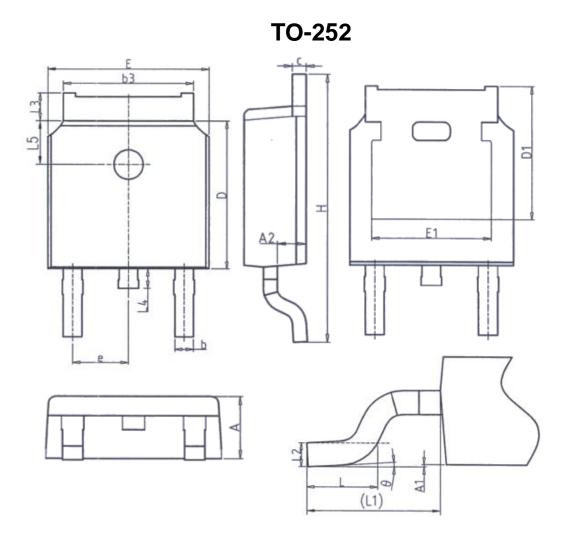




Unit: mm		
Symbol	Min.	Max.
Α	4. 37	4. 77
A1	1. 25	1. 45
A2	2. 20	2. 60
b	0. 70	0. 95
b2	1. 17	1. 47
С	0. 40	0. 65
D	15. 10	16. 10
D1	8. 80	9. 40
D2	5. 50	_

Unit: mm			
Symbol	Min.	Max.	
E	9. 70	10.30	
E3	7. 00	-	
е	2. 54BSC		
e1	5. 08BSC		
H1	6. 25	6. 85	
L	12. 75	13.80	
L1	- 3.40		
Р	3. 40	3. 80	
Q	2. 60	3. 00	





Unit: mm			
Symbol	Min.	Max.	
Α	2. 20	2. 40	
A1	0.00	0. 20	
A2	0. 97	1. 17	
b	0. 68	0.90	
b3	5. 20	5. 50	
С	0. 43	0. 63	
D	5. 98	6. 22	
D1	D1 5. 30REF		
E	6. 40	6. 80	
E1	4. 63	_	

Unit: mm			
Symbol	Min.	Max.	
е	2. 28	6BSC	
Н	9. 40	10.50	
L	1. 38	1. 75	
L1	2. 90REF		
L2	0. 51BSC		
L3	0.88	1. 28	
L4	_	1.00	
L5	1. 65	1. 95	
θ	0°	8°	



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